Welcome to Galaxy Examinator reports

Date: Tue Sep 3 00:21:20 2024
Product :
LotID :

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Tests Statistics

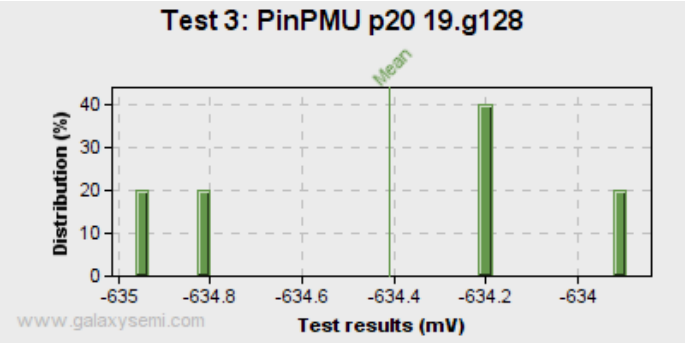
Test	Name	Type	Low L.	High L.	Source	Execs	Fails	Mean	Sigma	Cp	Cpk	Yield
0	Functional_T1	F	n/a .	n/a .	Samples	5	0	n/a .	n/a .	n/a .	n/a .	100.00 %
1	Functional_T2	F	n/a .	n/a .	Samples	5	0	n/a .	n/a .	n/a .	n/a .	100.00 %
2	Functional_T3	F	n/a .	n/a .	Samples	5	0	n/a .	n/a .	n/a .	n/a .	100.00 %
3	PinPMU p20 19.g128	P	−1200 mV	−100 mV	Samples	5	0	−634.411 mV	0.452759 mV	404.9	393.4	100.00 %
4	PinPMU p21 19.g126	P	−1200 mV	−100 mV	Samples	5	0	−634.787 mV	0.522088 mV	351.2	341.4	100.00 %
5	PinPMU p22 19.e126	P	−1200 mV	−100 mV	Samples	5	0	−634.679 mV	0.27719 mV	661.4	643.0	100.00 %
6	PinPMU p23 19.e124	P	−1200 mV	−100 mV	Samples	5	0	−634.738 mV	0.273022 mV	671.5	652.9	100.00 %
7	PinPMU p40 19.e130	P	−1200 mV	−100 mV	Samples	5	0	−635.045 mV	0.231439 mV	792.1	770.6	100.00 %
8	PinPMU p41 19.e139	P	−1200 mV	−100 mV	Samples	5	0	−634.975 mV	0.522049 mV	351.2	341.6	100.00 %
9	PinPMU p42 19.e147	P	−1200 mV	−100 mV	Samples	5	0	−635.002 mV	0.127686 mV	1435.8	1396.7	100.00 %
10	PinPMU p43 19.e151	P	−1200 mV	−100 mV	Samples	5	0	−634.628 mV	0.277426 mV	660.8	642.4	100.00 %
11	PinPMU p50 19.e128	P	−1200 mV	−100 mV	Samples	5	0	−634.497 mV	0.465627 mV	393.7	382.6	100.00 %
12	PinPMU p51 19.g149	P	−1200 mV	−100 mV	Samples	5	0	−631.74 mV	0.167176 mV	1096.6	1060.2	100.00 %
13	PinPMU p52 19.e137	P	−1200 mV	−100 mV	Samples	5	0	−633.085 mV	0.463042 mV	395.9	383.8	100.00 %
14	PinPMU p53 19.e135	P	−1200 mV	−100 mV	Samples	5	0	−633.294 mV	0.330803 mV	554.2	537.4	100.00 %
15	PinPMU p60 19.g130	P	−1200 mV	−100 mV	Samples	5	0	−632.656 mV	0.348051 mV	526.7	510.1	100.00 %
16	PinPMU p61 19.g104	P	−1200 mV	−100 mV	Samples	5	0	−632.711 mV	0.255378 mV	717.9	695.3	100.00 %
17	PinPMU p62 19.g102	P	−1200 mV	−100 mV	Samples	5	0	−632.844 mV	0.450134 mV	407.3	394.6	100.00 %
18	PinPMU p63 19.e102	P	−1200 mV	−100 mV	Samples	5	0	−632.67 mV	0.152588 mV	1201.5	1163.6	100.00 %
19	PinPMU p70 19.g139	P	−1200 mV	−100 mV	Samples	5	0	−634.562 mV	0.423609 mV	432.8	420.6	100.00 %
20	PinPMU p71 19.g147	P	−1200 mV	−100 mV	Samples	5	0	−632.871 mV	0.174045 mV	1053.4	1020.6	100.00 %
21	PinPMU p72 19.e104	P	−1200 mV	−100 mV	Samples	5	0	−632.904 mV	0.351479 mV	521.6	505.4	100.00 %
22	PinPMU p73 19.e108	P	−1200 mV	−100 mV	Samples	5	0	−632.706 mV	0.277231 mV	661.3	640.5	100.00 %
23	PinPMU cs 19.g106	P	−1200 mV	−100 mV	Samples	5	0	−633.886 mV	0.277298 mV	661.1	641.8	100.00 %
24	PinPMU prog 19.g124	P	−1200 mV	−100 mV	Samples	5	0	−634.943 mV	0.198975 mV	921.4	896.2	100.00 %
25	SeqLeakage1 p20 19.g128	P	−30 uA	10 uA	Samples	5	0	−0.794551 uA	0.0082032 uA	812.7	438.6	100.00 %
26	SeqLeakage1 p21 19.g126	P	−30 uA	10 uA	Samples	5	0	−0.79051 uA	0.0141029 uA	472.7	255.0	100.00 %
27	SeqLeakage1 p22 19.e126	P	−30 uA	10 uA	Samples	5	0	−0.788514 uA	0.00792845 uA	840.9	453.6	100.00 %
28	SeqLeakage1 p23 19.e124	P	−30 uA	10 uA	Samples	5	0	−0.789875 uA	0.00495619 uA	1345.1	725.7	100.00 %
29	SeqLeakage2 cs 19.g106	P	−30 uA	10 uA	Samples	5	0	0.0106357 uA	0.00745001 uA	894.9	447.0	100.00 %
30	SeqLeakage2 prog 19.g124	P	−30 uA	10 uA	Samples	5	0	−0.00595925 uA	0.00772365 uA	863.1	431.8	100.00 %
31	VBT_outpleakage1 p40 19.e130	P	−10 uA	20 uA	Samples	5	0	−0.00298809 uA	0.0109083 uA	458.4	305.5	100.00 %
Test	**Name**	**Type**	**Low L.**	**High L.**	**Source**	**Execs**	**Fails**	**Mean**	**Sigma**	**Cp**	**Cpk**	**Yield**
32	VBT_outpleakage1 p41 19.e139	P	−10 uA	20 uA	Samples	5	0	0.00199035 uA	0.00792601 uA	630.8	420.6	100.00 %
33	VBT_outpleakage1 p42 19.e147	P	−10 uA	20 uA	Samples	5	0	0.00494656 uA	0.00684062 uA	730.9	487.5	100.00 %
34	VBT_outpleakage1 p43 19.e151	P	−10 uA	20 uA	Samples	5	0	0.00374601 uA	0.012239 uA	408.5	272.5	100.00 %
35	VBT_outpleakage1 p50 19.e128	P	−10 uA	20 uA	Samples	5	0	0.00137038 uA	0.0108017 uA	462.9	308.6	100.00 %
36	VBT_outpleakage1 p51 19.g149	P	−10 uA	20 uA	Samples	5	0	0.00298456 uA	0.0130837 uA	382.2	254.8	100.00 %

37	VBT_outpleakage1 p52 19.e137	P	−10 uA	20 uA	Samples	5	0	−0.00474784 uA	0.00571521 uA	874.9	583.0	100.00 %
38	VBT_outpleakage1 p53 19.e135	P	−10 uA	20 uA	Samples	5	0	0.00365624 uA	0.0069521 uA	719.2	479.6	100.00 %
39	VBT_outpleakage1 p60 19.g130	P	−10 uA	20 uA	Samples	5	0	0.00474458 uA	0.0113325 uA	441.2	294.3	100.00 %
40	VBT_outpleakage1 p61 19.g104	P	−10 uA	20 uA	Samples	5	0	0.00389282 uA	0.00569667 uA	877.7	585.4	100.00 %
41	VBT_outpleakage1 p62 19.g102	P	−10 uA	20 uA	Samples	5	0	−0.00313774 uA	0.0161622 uA	309.4	206.2	100.00 %
42	VBT_outpleakage1 p63 19.e102	P	−10 uA	20 uA	Samples	5	0	0.000838792 uA	0.0113308 uA	441.3	294.2	100.00 %
43	VBT_outpleakage1 p70 19.g139	P	−10 uA	20 uA	Samples	5	0	0.000533749 uA	0.00696758 uA	717.6	478.4	100.00 %
44	VBT_outpleakage1 p71 19.g147	P	−10 uA	20 uA	Samples	5	0	0.00452456 uA	0.0167961 uA	297.7	198.5	100.00 %
45	VBT_outpleakage1 p72 19.e104	P	−10 uA	20 uA	Samples	5	0	−0.00167706 uA	0.00701563 uA	712.7	475.1	100.00 %
46	VBT_outpleakage1 p73 19.e108	P	−10 uA	20 uA	Samples	5	0	0.00541203 uA	0.00636382 uA	785.7	524.1	100.00 %
47	OutputZ_leak_vbt1 p40 19.e130	P	−10 uA	20 uA	Samples	5	0	0.00283485 uA	0.0112265 uA	445.4	297.0	100.00 %
48	OutputZ_leak_vbt1 p41 19.e139	P	−10 uA	20 uA	Samples	5	0	0.00459313 uA	0.0132526 uA	377.3	251.6	100.00 %
49	OutputZ_leak_vbt1 p42 19.e147	P	−10 uA	20 uA	Samples	5	0	−0.00144592 uA	0.0104677 uA	477.7	318.4	100.00 %
50	OutputZ_leak_vbt1 p43 19.e151	P	−10 uA	20 uA	Samples	5	0	−7.64492e−05 uA	0.0148889 uA	335.8	223.9	100.00 %
51	OutputZ_leak_vbt1 p50 19.e128	P	−10 uA	20 uA	Samples	5	0	−0.00182717 uA	0.00920854 uA	543.0	361.9	100.00 %
52	OutputZ_leak_vbt1 p51 19.g149	P	−10 uA	20 uA	Samples	5	0	0.0028315 uA	0.00503569 uA	992.9	662.1	100.00 %
53	OutputZ_leak_vbt1 p52 19.e137	P	−10 uA	20 uA	Samples	5	0	0.00796412 uA	0.00332035 uA	1505.9	1004.7	100.00 %
54	OutputZ_leak_vbt1 p53 19.e135	P	−10 uA	20 uA	Samples	5	0	0.00319921 uA	0.0116446 uA	429.4	286.3	100.00 %
55	OutputZ_leak_vbt1 p60 19.g130	P	−10 uA	20 uA	Samples	5	0	−0.00428543 uA	0.00520711 uA	960.2	639.9	100.00 %
56	OutputZ_leak_vbt1 p61 19.g104	P	−10 uA	20 uA	Samples	5	0	0.00725132 uA	0.0164277 uA	304.4	203.1	100.00 %
57	OutputZ_leak_vbt1 p62 19.g102	P	−10 uA	20 uA	Samples	5	0	0.0172193 uA	0.0186567 uA	268.0	179.0	100.00 %
58	OutputZ_leak_vbt1 p63 19.e102	P	−10 uA	20 uA	Samples	5	0	0.00312641 uA	0.00995105 uA	502.5	335.1	100.00 %
59	OutputZ_leak_vbt1 p70 19.g139	P	−10 uA	20 uA	Samples	5	0	−0.00297374 uA	0.00880347 uA	568.0	378.5	100.00 %
60	OutputZ_leak_vbt1 p71 19.g147	P	−10 uA	20 uA	Samples	5	0	0.0111197 uA	0.00899893 uA	555.6	370.8	100.00 %
61	OutputZ_leak_vbt1 p72 19.e104	P	−10 uA	20 uA	Samples	5	0	−0.00625084 uA	0.00825256 uA	605.9	403.7	100.00 %
62	OutputZ_leak_vbt1 p73 19.e108	P	−10 uA	20 uA	Samples	5	0	0.00144829 uA	0.00513039 uA	974.6	649.8	100.00 %
63	Functional_T4	F	n/a .	n/a .	Samples	5	0	n/a .	n/a .	n/a .	n/a .	100.00 %
Test	**Name**	**Type**	**Low L.**	**High L.**	**Source**	**Execs**	**Fails**	**Mean**	**Sigma**	**Cp**	**Cpk**	**Yield**
64	icc_static_vbt11 vcc 15.e201 <> Icc_static	P	10 uA	500 uA	Samples	5	0	21.2076 uA	0.186076 uA	438.9	20.08	100.00 %
65	Icc_dynamic vcc 15.e201 <> Icc_dynamic	P	10 uA	500 uA	Samples	5	0	20.8471 uA	0.210242 uA	388.4	17.20	100.00 %
67	Functional_T5 p50 19.e128	P	0 m	500 m	Samples	5	0	144 m	2 m	41.67	24.00	100.00 %
68	Functional_T5 p50 19.e128	P	2.8	3.4	Samples	5	0	3.2836	0.00181658	55.05	21.36	100.00 %
70	Functional_T6 A8 0	P	1 ns	100 ns	Samples	5	0	12 ns	2.82843 ns	5.83	1.30	100.00 %
71	Functional_T7 p53 19.e135	P	2.5 V	3.5 V	Samples	5	0	3.2822 V	0.00228037 V	73.09	31.84	100.00 %
72	Functional_T7 p53 19.e135	P	0 m	500 m	Samples	5	0	137 m	2.34521 m	35.53	19.47	100.00 %
73	Functional_T7	P	n/a .	n/a .	Summary	1	0	n/a .	0	n/a .	n/a .	100.00 %
74	Functional_T8 A8 0	P	1 ns	100 ns	Samples	5	3	556 ns	1236.55 ns	0.0133	−0.1229	40.00 %
75	Functional_T7	P	n/a .	n/a .	Summary	3	1	n/a .	0	n/a .	n/a .	66.67 %
76	Functional_T8	P	n/a .	n/a .	Summary	3	0	n/a .	0	n/a .	n/a .	100.00 %
77	Functional_T7	P	n/a .	n/a .	Summary	4	0	n/a .	0	n/a .	n/a .	100.00 %
78	Functional_T7	P	n/a .	n/a .	Summary	3	0	n/a .	0	n/a .	n/a .	100.00 %
79	Functional_T8	P	n/a .	n/a .	Summary	1	1	n/a .	0	n/a .	n/a .	0.00 %
80	Functional_T7	P	n/a .	n/a .	Summary	2	2	n/a .	0	n/a .	n/a .	0.00 %
81	Functional_T7	P	n/a .	n/a .	Summary	2	1	n/a .	0	n/a .	n/a .	50.00 %
82	Functional_T8	P	n/a .	n/a .	Summary	1	1	n/a .	0	n/a .	n/a .	0.00 %
83	Functional_T7	P	n/a .	n/a .	Summary	2	1	n/a .	0	n/a .	n/a .	50.00 %
84	Functional_T7	P	n/a .	n/a .	Summary	2	0	n/a .	0	n/a .	n/a .	100.00 %

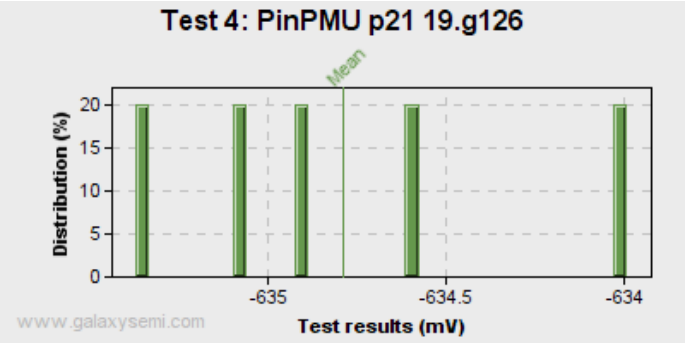
85	Functional_T8	P	n/a .	n/a .	Summary	1	1	n/a .	0	n/a .	n/a .	0.00 %
86	Functional_T8	P	n/a .	n/a .	Summary	1	0	n/a .	0	n/a .	n/a .	100.00 %
87	Functional_T8	P	n/a .	n/a .	Summary	1	1	n/a .	0	n/a .	n/a .	0.00 %
88	Functional_T8	P	n/a .	n/a .	Summary	1	0	n/a .	0	n/a .	n/a .	100.00 %
89	Functional_T8	P	n/a .	n/a .	Summary	1	1	n/a .	0	n/a .	n/a .	0.00 %
90	Functional_T8	P	n/a .	n/a .	Summary	1	0	n/a .	0	n/a .	n/a .	100.00 %
91	Functional_T8	P	n/a .	n/a .	Summary	1	0	n/a .	0	n/a .	n/a .	100.00 %
92	Functional_T8	P	n/a .	n/a .	Summary	1	1	n/a .	0	n/a .	n/a .	0.00 %
93	Functional_T8	P	n/a .	n/a .	Summary	1	1	n/a .	0	n/a .	n/a .	0.00 %
94	Functional_T8	P	n/a .	n/a .	Summary	1	0	n/a .	0	n/a .	n/a .	100.00 %
786000	Soft_Bin parameter	–	n/a .	n/a .	Samples	5	0	1	0	n/a .	n/a .	100.00 %
786001	Hard_Bin parameter	–	n/a .	n/a .	Samples	5	0	1	0	n/a .	n/a .	100.00 %
786002	Die_X parameter	–	n/a .	n/a .	Samples	5	0	0.4	0.547723	n/a .	n/a .	100.00 %
Test	**Name**	**Type**	**Low L.**	**High L.**	**Source**	**Execs**	**Fails**	**Mean**	**Sigma**	**Cp**	**Cpk**	**Yield**
786003	Die_Y parameter	–	n/a .	n/a .	Samples	5	0	1.2	0.83666	n/a .	n/a .	100.00 %
786004	Test_Time parameter	–	0.0 sec	n/a .	Samples	5	0	2.687 sec	0.0589067 sec	n/a .	15.20	100.00 %
786006	Testing_Site parameter	–	n/a .	n/a .	Samples	5	0	0	0	n/a .	n/a .	100.00 %
786007	Part_ID parameter	–	n/a .	n/a .	Samples	5	0	20	1.58114	n/a .	n/a .	100.00 %

Histogram of Tests

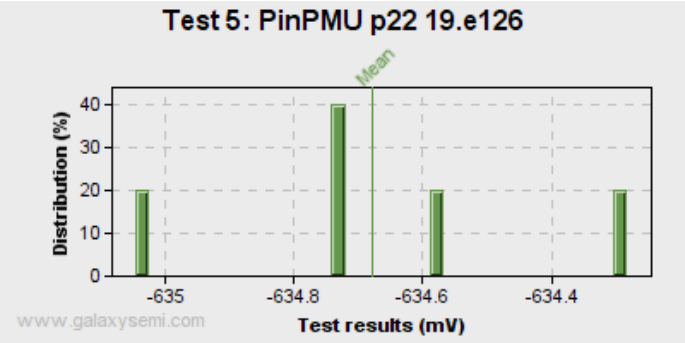
Test	3
Name	PinPMU p20 19.g128
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	5 / 0 (0.00%)
Mean	−634.411 mV
Sigma	0.452759 mV
Range	1.06835 mV
Cp / Cpk	404.9 / 393.4
Samples	5



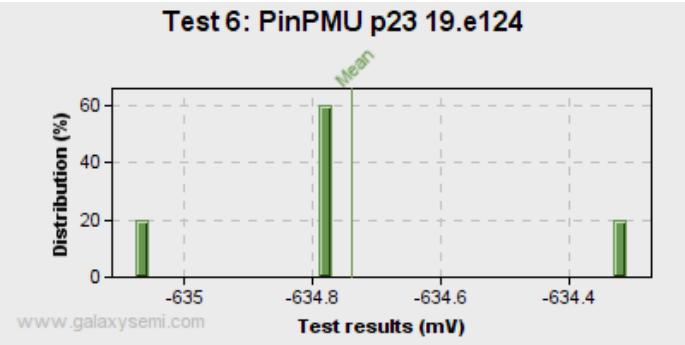
Test	4
Name	PinPMU p21 19.g126
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	5 / 0 (0.00%)
Mean	−634.787 mV
Sigma	0.522088 mV
Range	1.37371 mV
Cp / Cpk	351.2 / 341.4
Samples	5



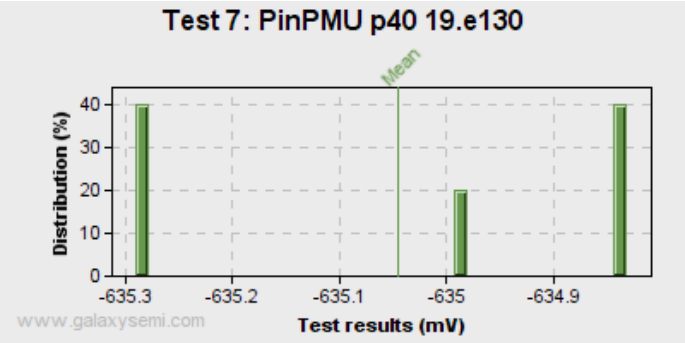
Test	5
Name	PinPMU p22 19.e126
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	5 / 0 (0.00%)
Mean	−634.679 mV
Sigma	0.27719 mV
Range	0.762939 mV
Cp / Cpk	661.4 / 643.0
Samples	5



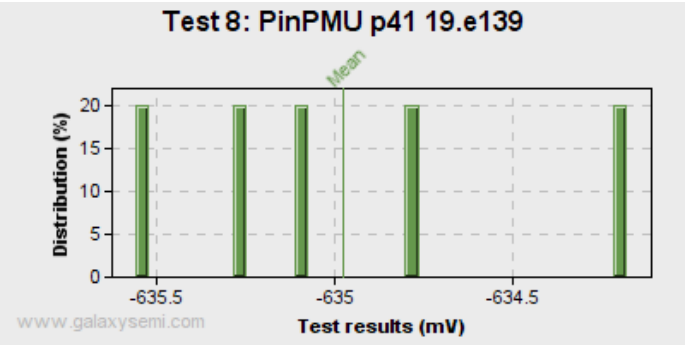
Test	6
Name	PinPMU p23 19.e124
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	5 / 0 (0.00%)
Mean	−634.738 mV
Sigma	0.273022 mV
Range	0.763118 mV
Cp / Cpk	671.5 / 652.9
Samples	5



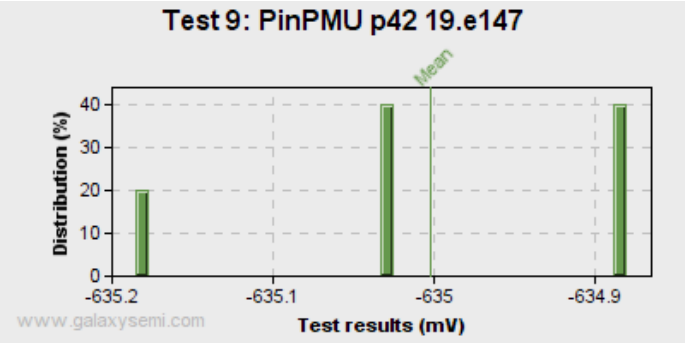
Test	7
Name	PinPMU p40 19.e130
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	5 / 0 (0.00%)
Mean	−635.045 mV
Sigma	0.231439 mV
Range	0.457823 mV
Cp / Cpk	792.1 / 770.6
Samples	5



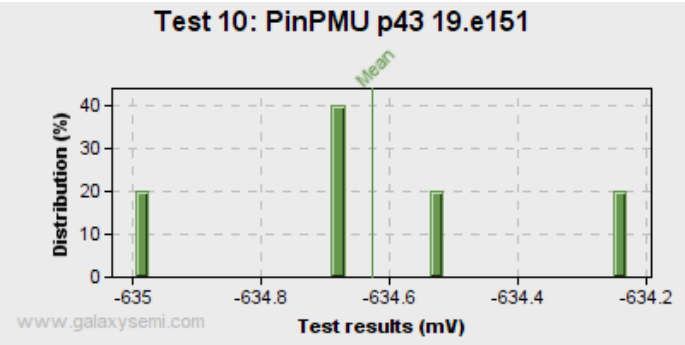
Test	8
Name	PinPMU p41 19.e139
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	5 / 0 (0.00%)
Mean	−634.975 mV
Sigma	0.522049 mV
Range	1.37359 mV
Cp / Cpk	351.2 / 341.6
Samples	5



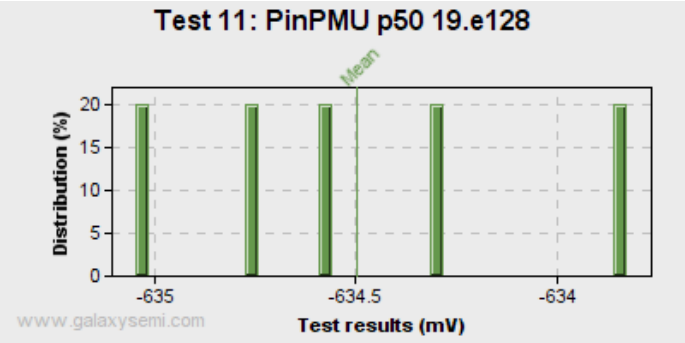
Test	9
Name	PinPMU p42 19.e147
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	5 / 0 (0.00%)
Mean	−635.002 mV
Sigma	0.127686 mV
Range	0.305235 mV
Cp / Cpk	1435.8 / 1396.7
Samples	5



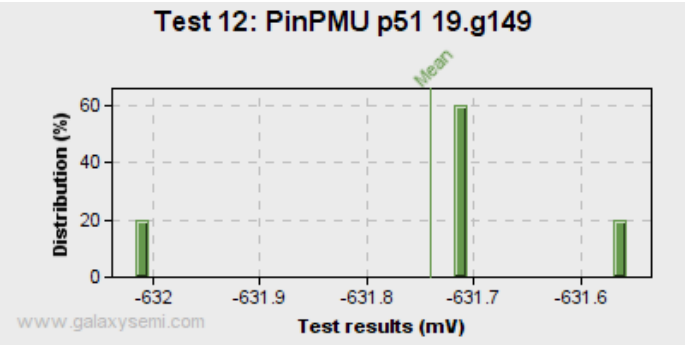
Test	10
Name	PinPMU p43 19.e151
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	5 / 0 (0.00%)
Mean	−634.628 mV
Sigma	0.277426 mV
Range	0.763595 mV
Cp / Cpk	660.8 / 642.4
Samples	5



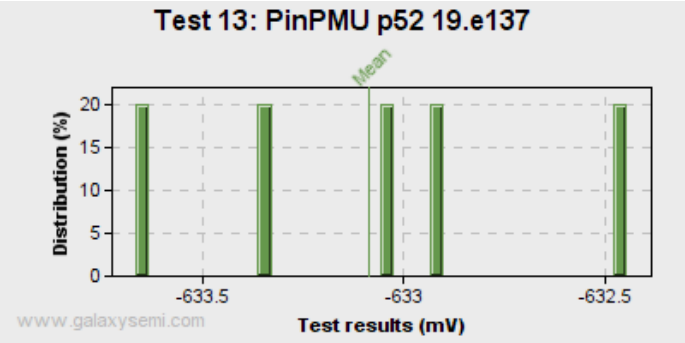
Test	11
Name	PinPMU p50 19.e128
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	5 / 0 (0.00%)
Mean	−634.497 mV
Sigma	0.465627 mV
Range	1.22148 mV
Cp / Cpk	393.7 / 382.6
Samples	5



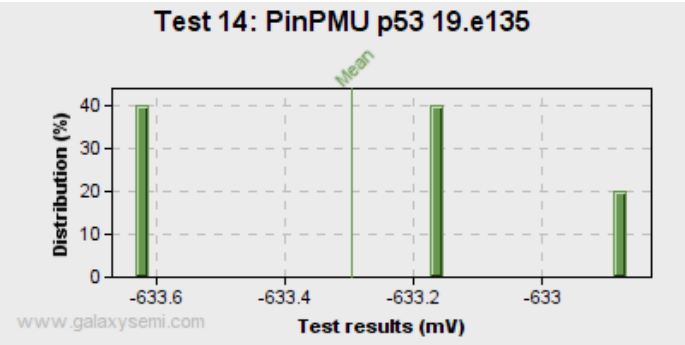
Test	12
Name	PinPMU p51 19.g149
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	5 / 0 (0.00%)
Mean	−631.74 mV
Sigma	0.167176 mV
Range	0.457823 mV
Cp / Cpk	1096.6 / 1060.2
Samples	5



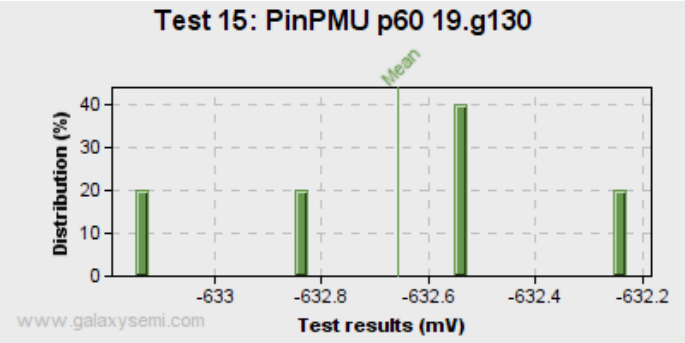
Test	13
Name	PinPMU p52 19.e137
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	5 / 0 (0.00%)
Mean	−633.085 mV
Sigma	0.463042 mV
Range	1.2213 mV
Cp / Cpk	395.9 / 383.8
Samples	5



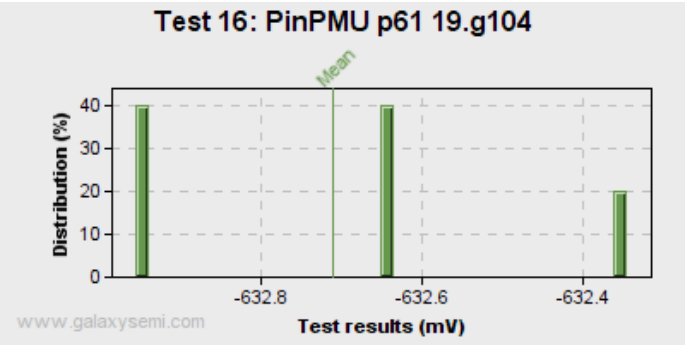
Test	14
Name	PinPMU p53 19.e135
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	5 / 0 (0.00%)
Mean	−633.294 mV
Sigma	0.330803 mV
Range	0.762939 mV
Cp / Cpk	554.2 / 537.4
Samples	5



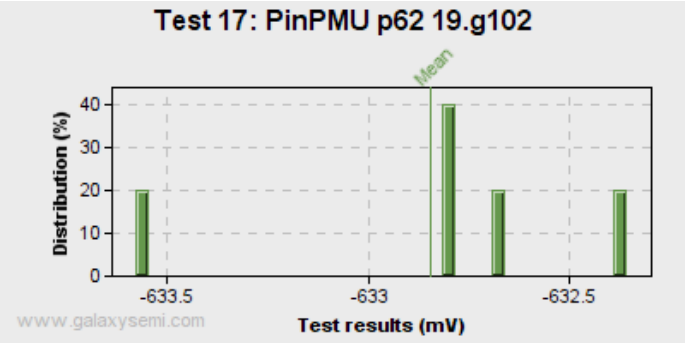
Test	15
Name	PinPMU p60 19.g130
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	5 / 0 (0.00%)
Mean	−632.656 mV
Sigma	0.348051 mV
Range	0.915766 mV
Cp / Cpk	526.7 / 510.1
Samples	5



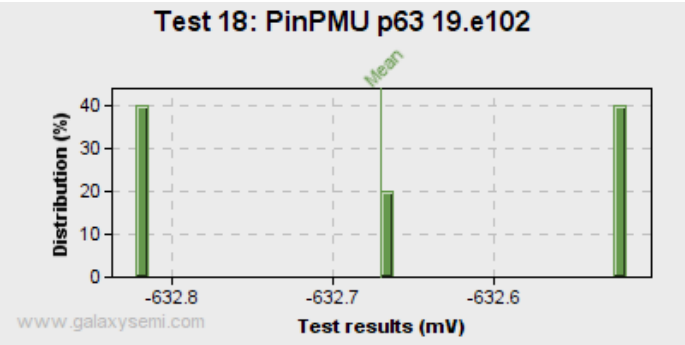
Test	16
Name	PinPMU p61 19.g104
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	5 / 0 (0.00%)
Mean	−632.711 mV
Sigma	0.255378 mV
Range	0.610471 mV
Cp / Cpk	717.9 / 695.3
Samples	5



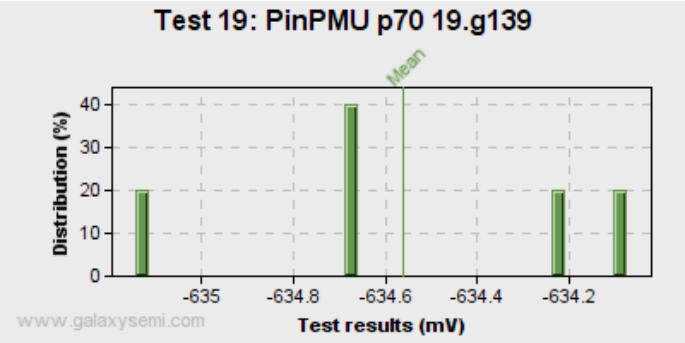
Test	17
Name	PinPMU p62 19.g102
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	5 / 0 (0.00%)
Mean	−632.844 mV
Sigma	0.450134 mV
Range	1.22088 mV
Cp / Cpk	407.3 / 394.6
Samples	5



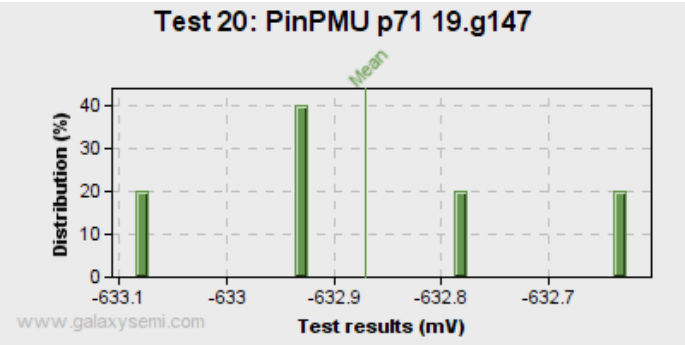
Test	18
Name	PinPMU p63 19.e102
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	5 / 0 (0.00%)
Mean	−632.67 mV
Sigma	0.152588 mV
Range	0.305176 mV
Cp / Cpk	1201.5 / 1163.6
Samples	5



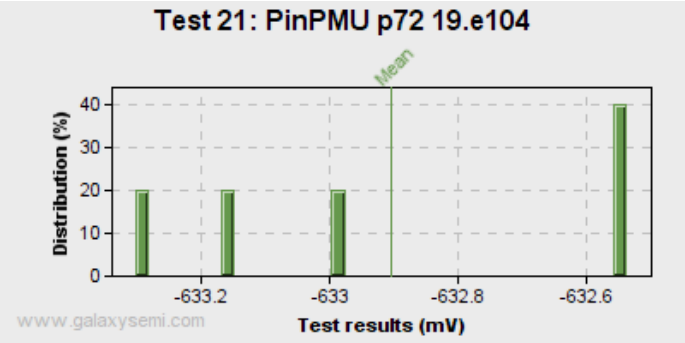
Test	19
Name	PinPMU p70 19.g139
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	5 / 0 (0.00%)
Mean	−634.562 mV
Sigma	0.423609 mV
Range	1.06859 mV
Cp / Cpk	432.8 / 420.6
Samples	5



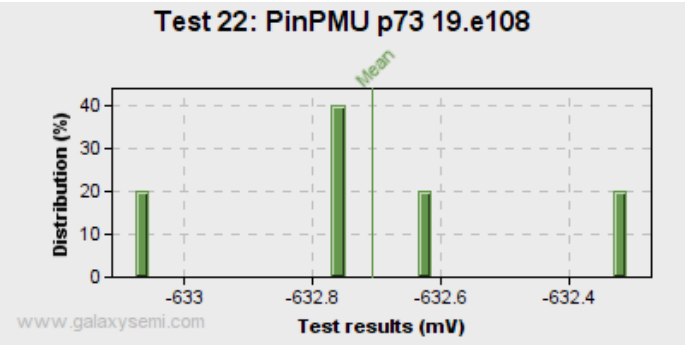
Test	20
Name	PinPMU p71 19.g147
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	5 / 0 (0.00%)
Mean	−632.871 mV
Sigma	0.174045 mV
Range	0.457942 mV
Cp / Cpk	1053.4 / 1020.6
Samples	5



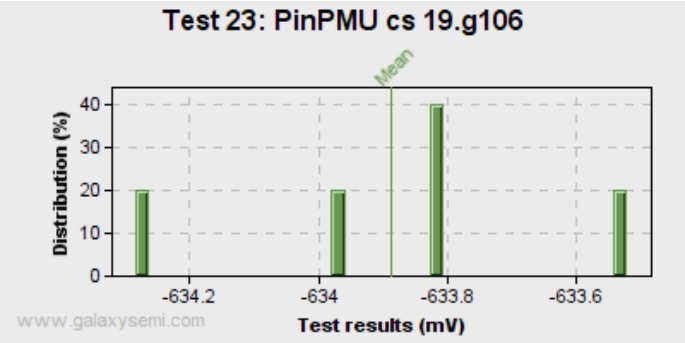
Test	21
Name	PinPMU p72 19.e104
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	5 / 0 (0.00%)
Mean	−632.904 mV
Sigma	0.351479 mV
Range	0.763357 mV
Cp / Cpk	521.6 / 505.4
Samples	5



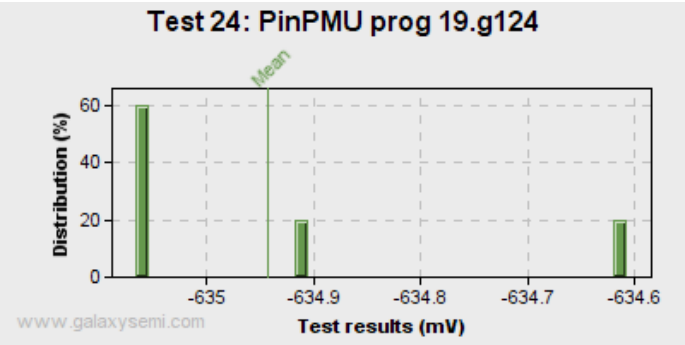
Test	22
Name	PinPMU p73 19.e108
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	5 / 0 (0.00%)
Mean	−632.706 mV
Sigma	0.277231 mV
Range	0.763059 mV
Cp / Cpk	661.3 / 640.5
Samples	5



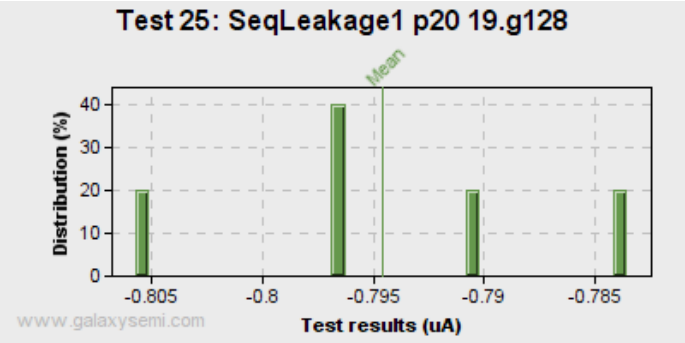
Test	23
Name	PinPMU cs 19.g106
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	5 / 0 (0.00%)
Mean	−633.886 mV
Sigma	0.277298 mV
Range	0.763237 mV
Cp / Cpk	661.1 / 641.8
Samples	5



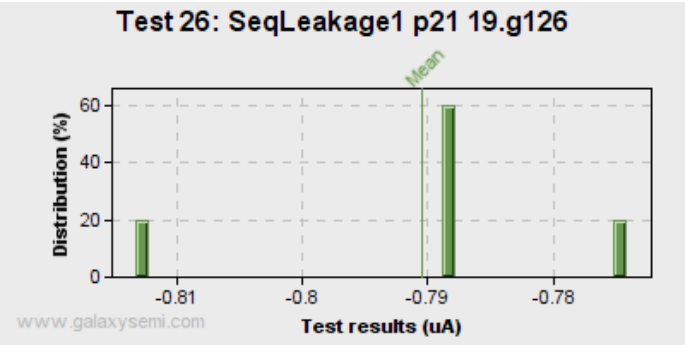
Test	24
Name	PinPMU prog 19.g124
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	5 / 0 (0.00%)
Mean	−634.943 mV
Sigma	0.198975 mV
Range	0.457823 mV
Cp / Cpk	921.4 / 896.2
Samples	5



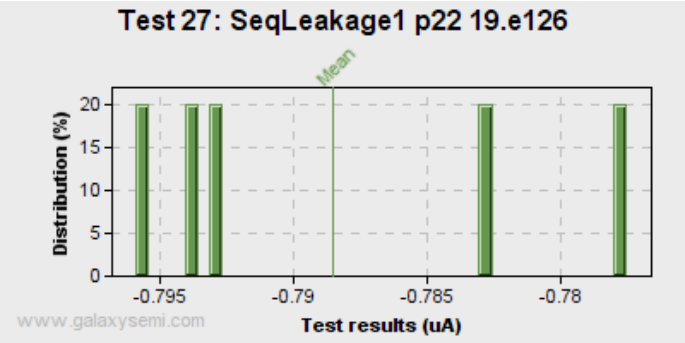
Test	25
Name	SeqLeakage1 p20 19.g128
Test type	Parametric
Low limit	–30 uA
High limit	10 uA
Exec / Fails	5 / 0 (0.00%)
Mean	–0.794551 uA
Sigma	0.0082032 uA
Range	0.0221069 uA
Cp / Cpk	812.7 / 438.6
Samples	5



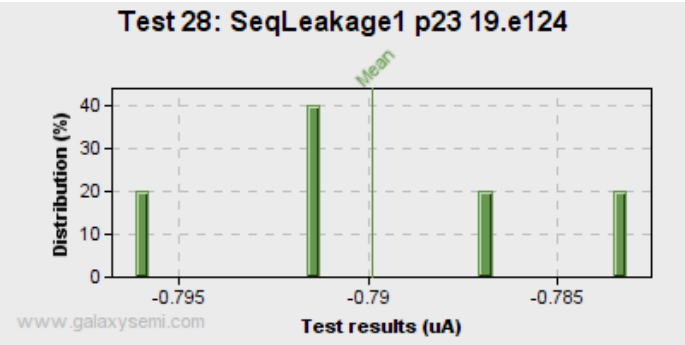
Test	26
Name	SeqLeakage1 p21 19.g126
Test type	Parametric
Low limit	–30 uA
High limit	10 uA
Exec / Fails	5 / 0 (0.00%)
Mean	–0.79051 uA
Sigma	0.0141029 uA
Range	0.039047 uA
Cp / Cpk	472.7 / 255.0
Samples	5



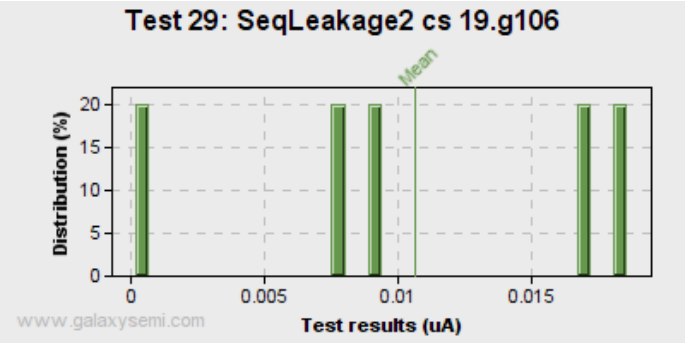
Test	27
Name	SeqLeakage1 p22 19.e126
Test type	Parametric
Low limit	–30 uA
High limit	10 uA
Exec / Fails	5 / 0 (0.00%)
Mean	–0.788514 uA
Sigma	0.00792845 uA
Range	0.0183696 uA
Cp / Cpk	840.9 / 453.6
Samples	5



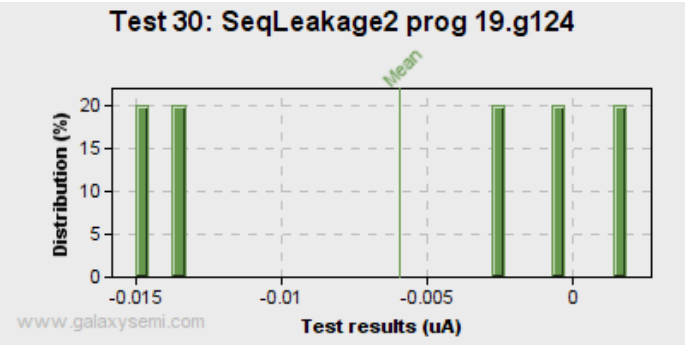
Test	28
Name	SeqLeakage1 p23 19.e124
Test type	Parametric
Low limit	–30 uA
High limit	10 uA
Exec / Fails	5 / 0 (0.00%)
Mean	–0.789875 uA
Sigma	0.00495619 uA
Range	0.01297 uA
Cp / Cpk	1345.1 / 725.7
Samples	5



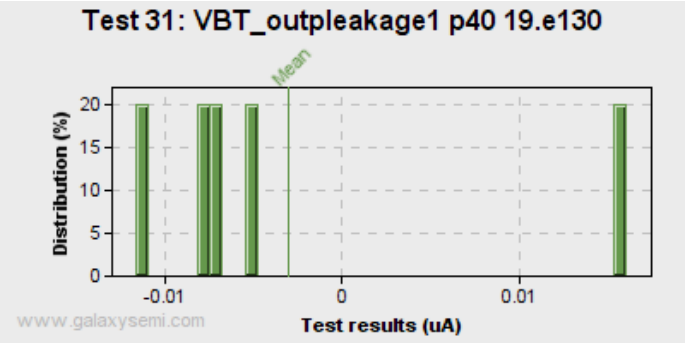
Test	29
Name	SeqLeakage2 cs 19.g106
Test type	Parametric
Low limit	−30 uA
High limit	10 uA
Exec / Fails	5 / 0 (0.00%)
Mean	0.0106357 uA
Sigma	0.00745001 uA
Range	0.0183639 uA
Cp / Cpk	894.9 / 447.0
Samples	5



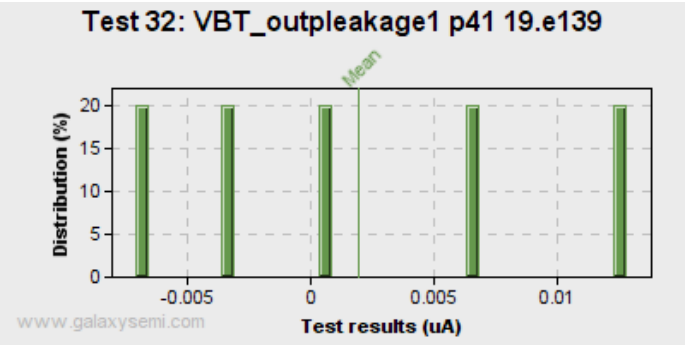
Test	30
Name	SeqLeakage2 prog 19.g124
Test type	Parametric
Low limit	−30 uA
High limit	10 uA
Exec / Fails	5 / 0 (0.00%)
Mean	−0.00595925 uA
Sigma	0.00772365 uA
Range	0.0168081 uA
Cp / Cpk	863.1 / 431.8
Samples	5



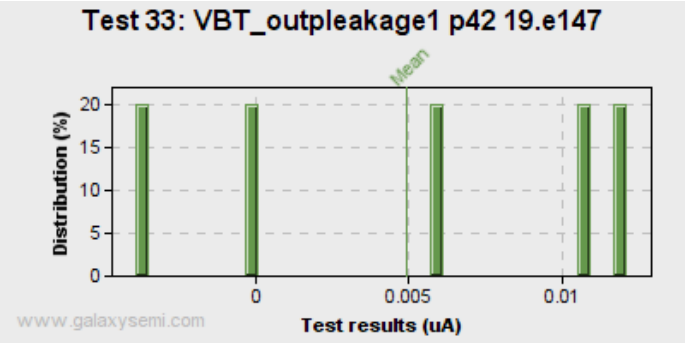
Test	31
Name	VBT_outpleakage1 p40 19.e130
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	5 / 0 (0.00%)
Mean	−0.00298809 uA
Sigma	0.0109083 uA
Range	0.0275824 uA
Cp / Cpk	458.4 / 305.5
Samples	5



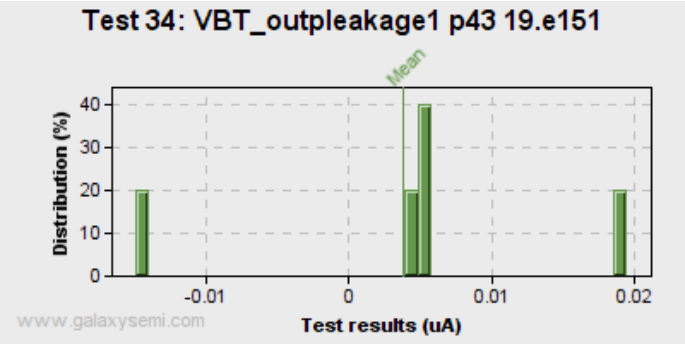
Test	32
Name	VBT_outpleakage1 p41 19.e139
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	5 / 0 (0.00%)
Mean	0.00199035 uA
Sigma	0.00792601 uA
Range	0.0199035 uA
Cp / Cpk	630.8 / 420.6
Samples	5



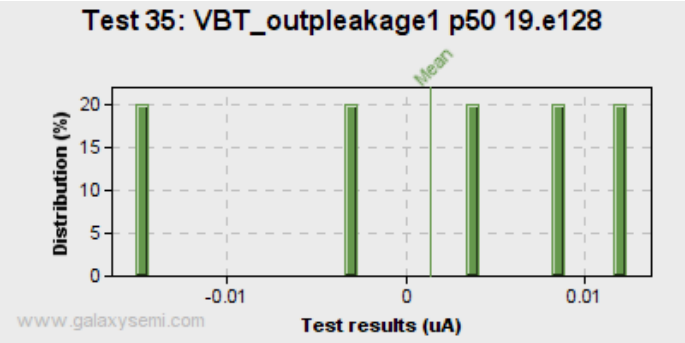
Test	33
Name	VBT_outpleakage1 p42 19.e147
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	5 / 0 (0.00%)
Mean	0.00494656 uA
Sigma	0.00684062 uA
Range	0.0159812 uA
Cp / Cpk	730.9 / 487.5
Samples	5



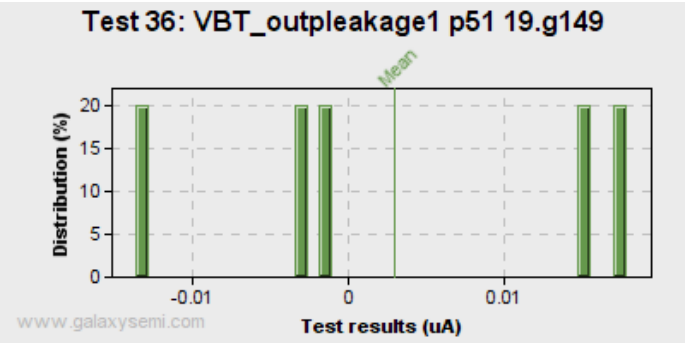
Test	34
Name	VBT_outpleakage1 p43 19.e151
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	5 / 0 (0.00%)
Mean	0.00374601 uA
Sigma	0.012239 uA
Range	0.0344021 uA
Cp / Cpk	408.5 / 272.5
Samples	5



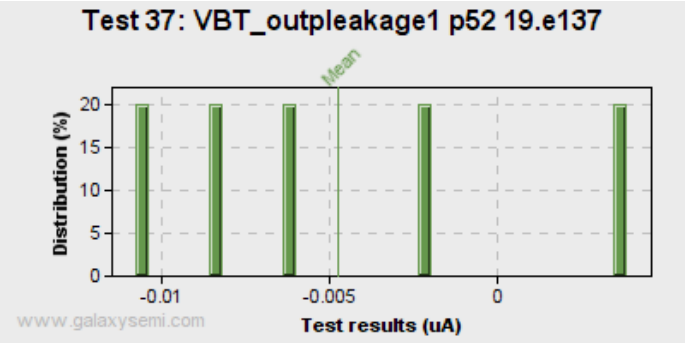
Test	35
Name	VBT_outpleakage1 p50 19.e128
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	5 / 0 (0.00%)
Mean	0.00137038 uA
Sigma	0.0108017 uA
Range	0.0274076 uA
Cp / Cpk	462.9 / 308.6
Samples	5



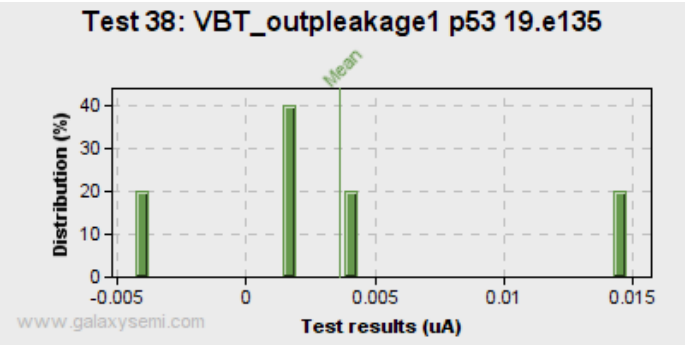
Test	36
Name	VBT_outpleakage1 p51 19.g149
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	5 / 0 (0.00%)
Mean	0.00298456 uA
Sigma	0.0130837 uA
Range	0.0313761 uA
Cp / Cpk	382.2 / 254.8
Samples	5



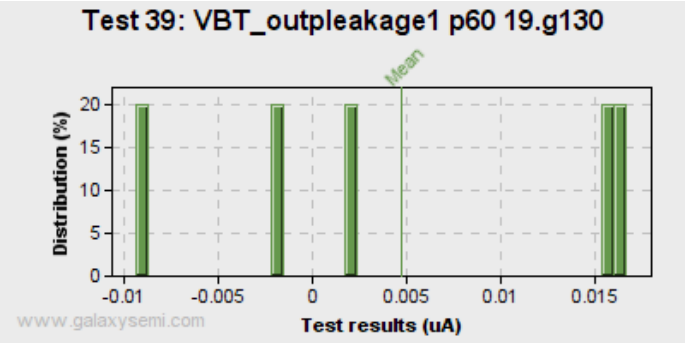
Test	37
Name	VBT_outpleakage1 p52 19.e137
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	5 / 0 (0.00%)
Mean	−0.00474784 uA
Sigma	0.00571521 uA
Range	0.0145498 uA
Cp / Cpk	874.9 / 583.0
Samples	5



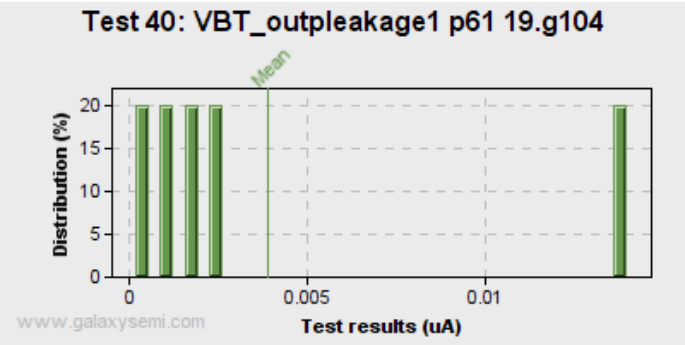
Test	38
Name	VBT_outpleakage1 p53 19.e135
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	5 / 0 (0.00%)
Mean	0.00365624 uA
Sigma	0.0069521 uA
Range	0.0190429 uA
Cp / Cpk	719.2 / 479.6
Samples	5



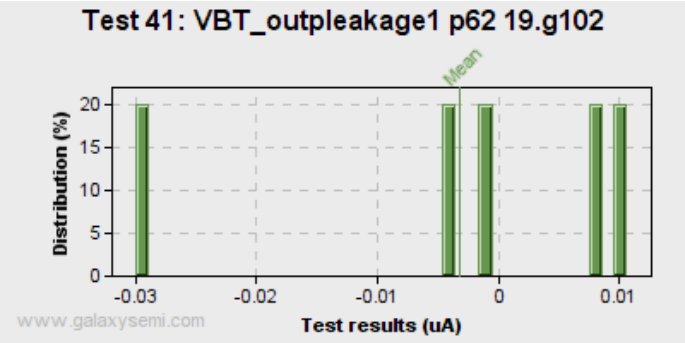
Test	39
Name	VBT_outpleakage1 p60 19.g130
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	5 / 0 (0.00%)
Mean	0.00474458 uA
Sigma	0.0113325 uA
Range	0.0260187 uA
Cp / Cpk	441.2 / 294.3
Samples	5



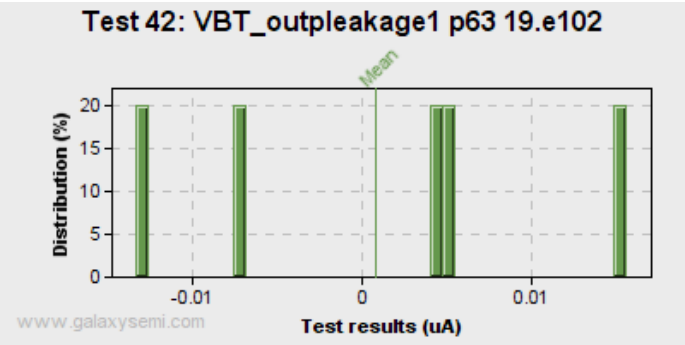
Test	40
Name	VBT_outpleakage1 p61 19.g104
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	5 / 0 (0.00%)
Mean	0.00389282 uA
Sigma	0.00569667 uA
Range	0.0137394 uA
Cp / Cpk	877.7 / 585.4
Samples	5



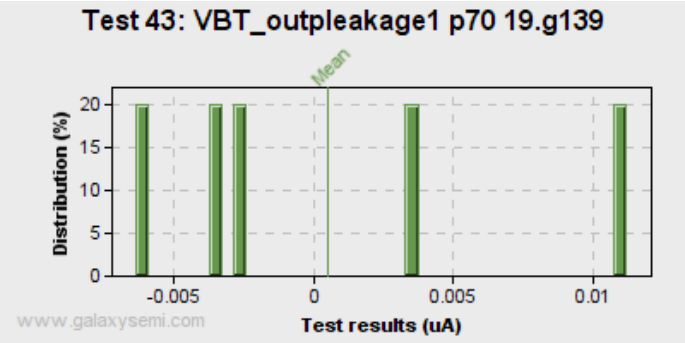
Test	41
Name	VBT_outpleakage1 p62 19.g102
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	5 / 0 (0.00%)
Mean	−0.00313774 uA
Sigma	0.0161622 uA
Range	0.040561 uA
Cp / Cpk	309.4 / 206.2
Samples	5



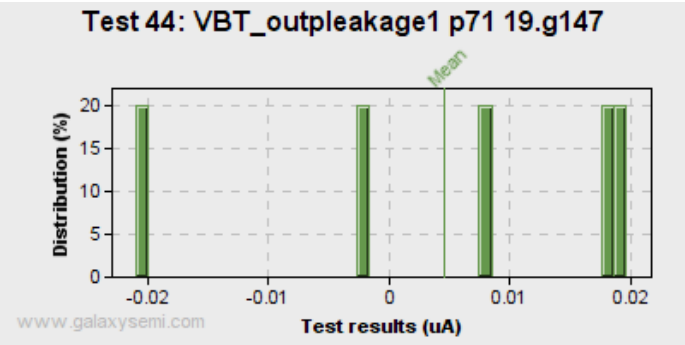
Test	42
Name	VBT_outpleakage1 p63 19.e102
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	5 / 0 (0.00%)
Mean	0.000838792 uA
Sigma	0.0113308 uA
Range	0.0289764 uA
Cp / Cpk	441.3 / 294.2
Samples	5



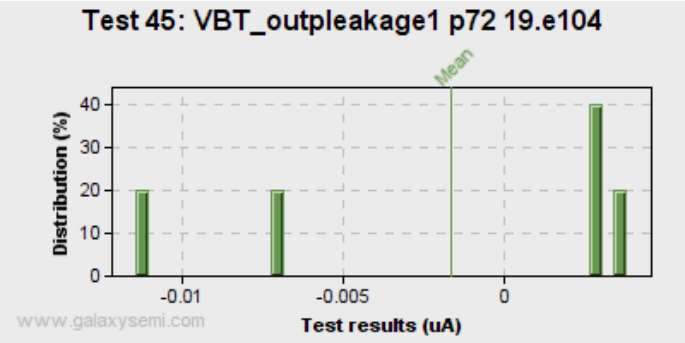
Test	43
Name	VBT_outpleakage1 p70 19.g139
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	5 / 0 (0.00%)
Mean	0.000533749 uA
Sigma	0.00696758 uA
Range	0.0175375 uA
Cp / Cpk	717.6 / 478.4
Samples	5



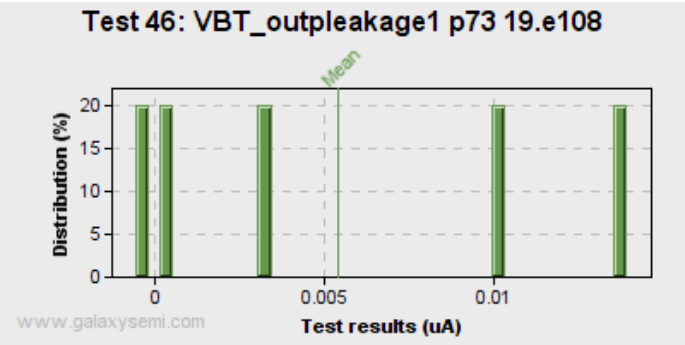
Test	44
Name	VBT_outpleakage1 p71 19.g147
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	5 / 0 (0.00%)
Mean	0.00452456 uA
Sigma	0.0167961 uA
Range	0.0406443 uA
Cp / Cpk	297.7 / 198.5
Samples	5



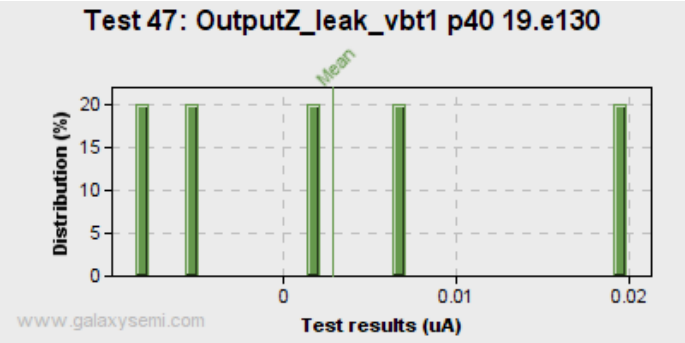
Test	45
Name	VBT_outpleakage1 p72 19.e104
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	5 / 0 (0.00%)
Mean	−0.00167706 uA
Sigma	0.00701563 uA
Range	0.015246 uA
Cp / Cpk	712.7 / 475.1
Samples	5



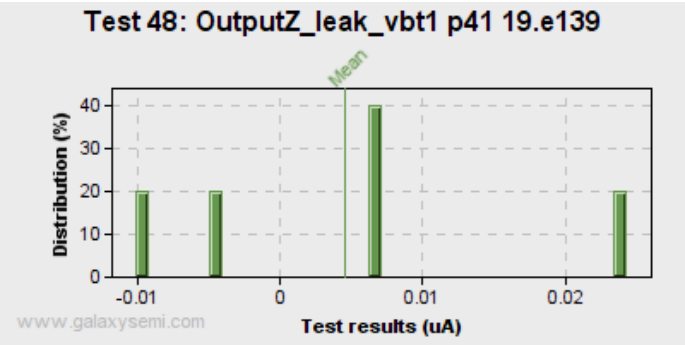
Test	46
Name	VBT_outpleakage1 p73 19.e108
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	5 / 0 (0.00%)
Mean	0.00541203 uA
Sigma	0.00636382 uA
Range	0.0144829 uA
Cp / Cpk	785.7 / 524.1
Samples	5



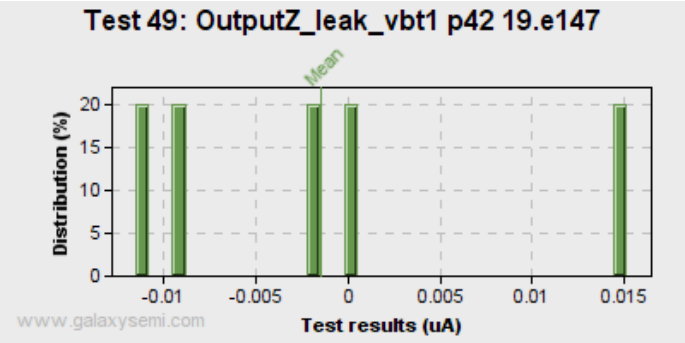
Test	47
Name	OutputZ_leak_vbt1 p40 19.e130
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	5 / 0 (0.00%)
Mean	0.00283485 uA
Sigma	0.0112265 uA
Range	0.0283485 uA
Cp / Cpk	445.4 / 297.0
Samples	5



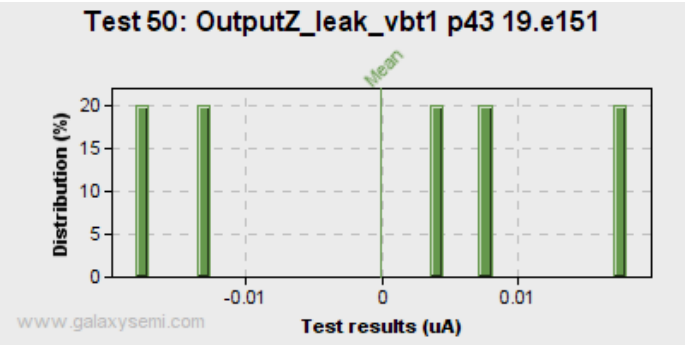
Test	48
Name	OutputZ_leak_vbt1 p41 19.e139
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	5 / 0 (0.00%)
Mean	0.00459313 uA
Sigma	0.0132526 uA
Range	0.0344484 uA
Cp / Cpk	377.3 / 251.6
Samples	5



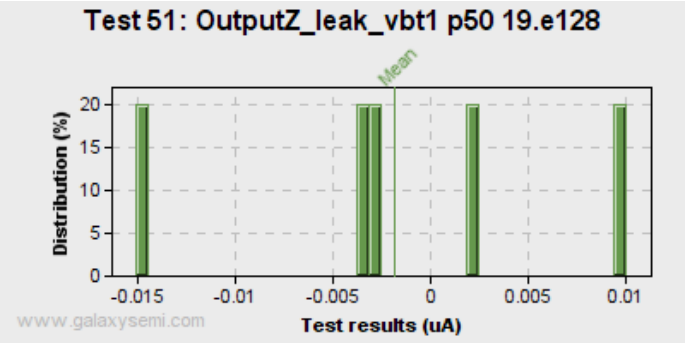
Test	49
Name	OutputZ_leak_vbt1 p42 19.e147
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	5 / 0 (0.00%)
Mean	−0.00144592 uA
Sigma	0.0104677 uA
Range	0.0266353 uA
Cp / Cpk	477.7 / 318.4
Samples	5



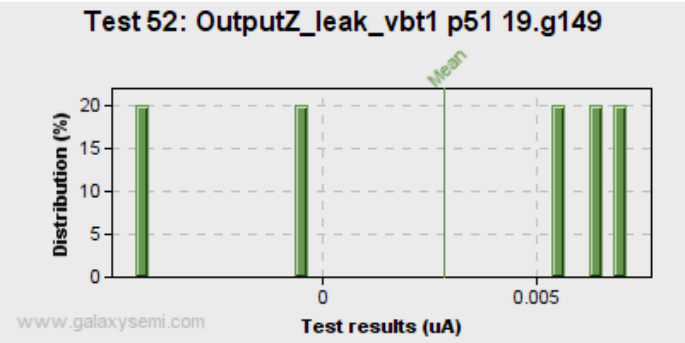
Test	50
Name	OutputZ_leak_vbt1 p43 19.e151
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	5 / 0 (0.00%)
Mean	−7.64492e−05 uA
Sigma	0.0148889 uA
Range	0.0359311 uA
Cp / Cpk	335.8 / 223.9
Samples	5



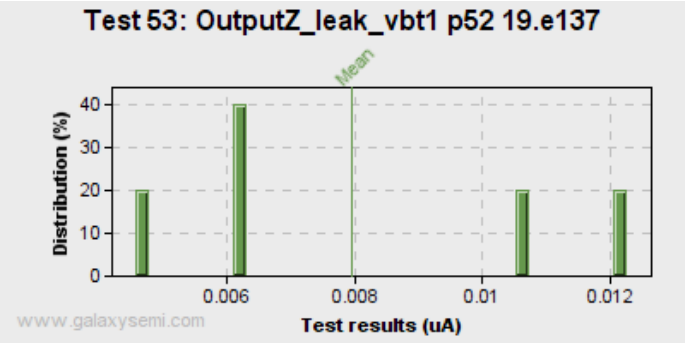
Test	51
Name	OutputZ_leak_vbt1 p50 19.e128
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	5 / 0 (0.00%)
Mean	−0.00182717 uA
Sigma	0.00920854 uA
Range	0.0251236 uA
Cp / Cpk	543.0 / 361.9
Samples	5



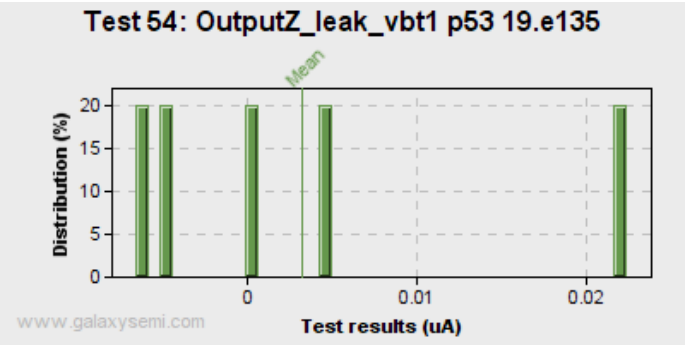
Test	52
Name	OutputZ_leak_vbt1 p51 19.g149
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	5 / 0 (0.00%)
Mean	0.0028315 uA
Sigma	0.00503569 uA
Range	0.0114791 uA
Cp / Cpk	992.9 / 662.1
Samples	5



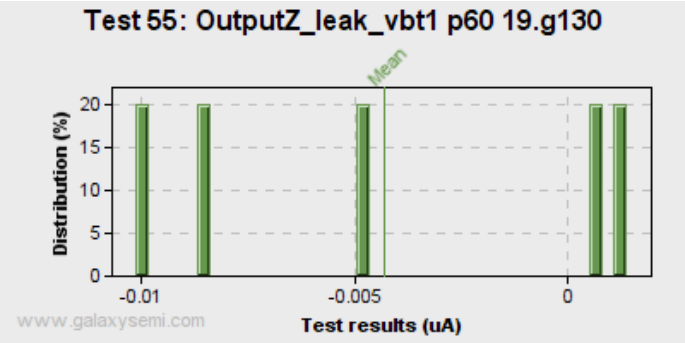
Test	53
Name	OutputZ_leak_vbt1 p52 19.e137
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	5 / 0 (0.00%)
Mean	0.00796412 uA
Sigma	0.00332035 uA
Range	0.00765781 uA
Cp / Cpk	1505.9 / 1004.7
Samples	5



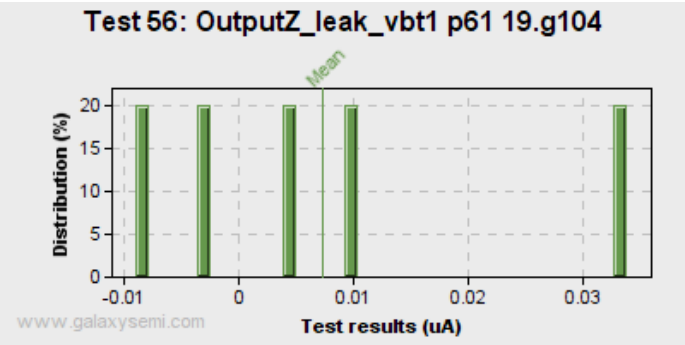
Test	54
Name	OutputZ_leak_vbt1 p53 19.e135
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	5 / 0 (0.00%)
Mean	0.00319921 uA
Sigma	0.0116446 uA
Range	0.0289452 uA
Cp / Cpk	429.4 / 286.3
Samples	5



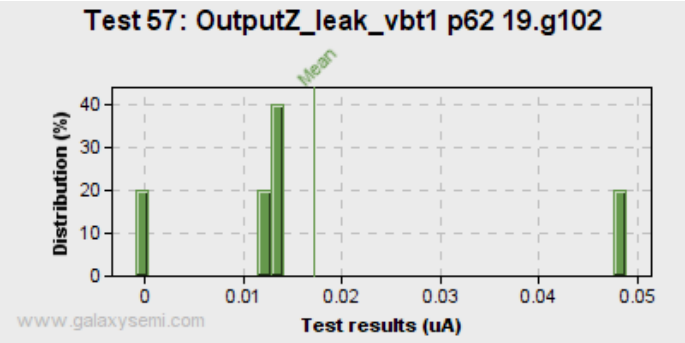
Test	55
Name	OutputZ_leak_vbt1 p60 19.g130
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	5 / 0 (0.00%)
Mean	−0.00428543 uA
Sigma	0.00520711 uA
Range	0.0114788 uA
Cp / Cpk	960.2 / 639.9
Samples	5



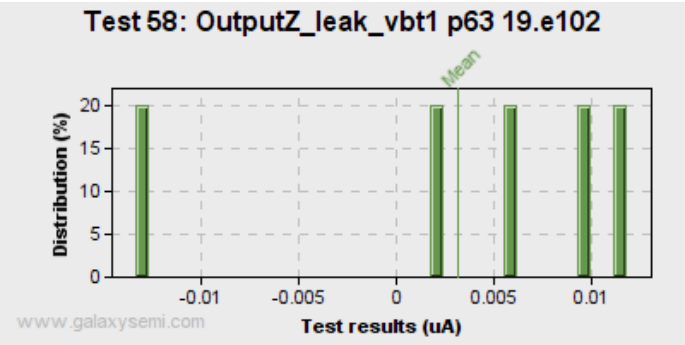
Test	56
Name	OutputZ_leak_vbt1 p61 19.g104
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	5 / 0 (0.00%)
Mean	0.00725132 uA
Sigma	0.0164277 uA
Range	0.0427446 uA
Cp / Cpk	304.4 / 203.1
Samples	5



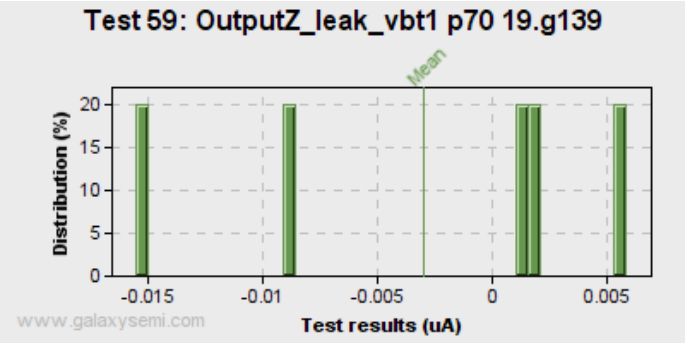
Test	57
Name	OutputZ_leak_vbt1 p62 19.g102
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	5 / 0 (0.00%)
Mean	0.0172193 uA
Sigma	0.0186567 uA
Range	0.0497446 uA
Cp / Cpk	268.0 / 179.0
Samples	5



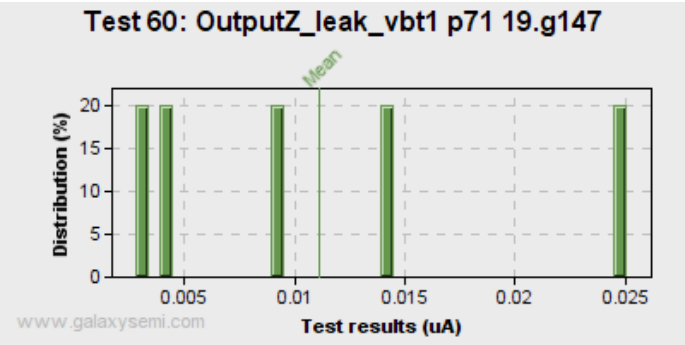
Test	58
Name	OutputZ_leak_vbt1 p63 19.e102
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	5 / 0 (0.00%)
Mean	0.00312641 uA
Sigma	0.00995105 uA
Range	0.0251637 uA
Cp / Cpk	502.5 / 335.1
Samples	5



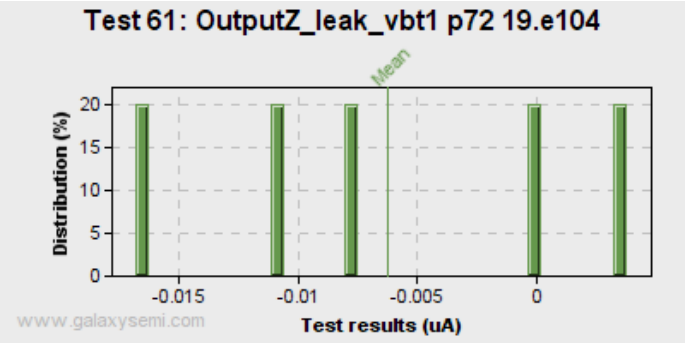
Test	59
Name	OutputZ_leak_vbt1 p70 19.g139
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	5 / 0 (0.00%)
Mean	−0.00297374 uA
Sigma	0.00880347 uA
Range	0.0213499 uA
Cp / Cpk	568.0 / 378.5
Samples	5



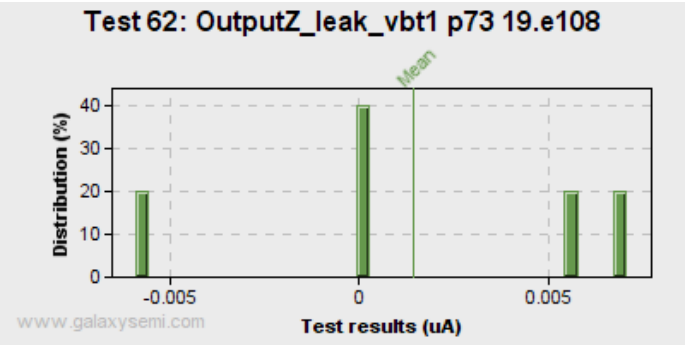
Test	60
Name	OutputZ_leak_vbt1 p71 19.g147
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	5 / 0 (0.00%)
Mean	0.0111197 uA
Sigma	0.00899893 uA
Range	0.0222393 uA
Cp / Cpk	555.6 / 370.8
Samples	5



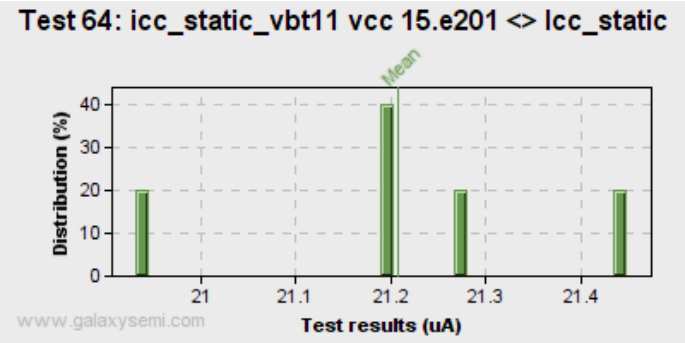
Test	61
Name	OutputZ_leak_vbt1 p72 19.e104
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	5 / 0 (0.00%)
Mean	−0.00625084 uA
Sigma	0.00825256 uA
Range	0.020582 uA
Cp / Cpk	605.9 / 403.7
Samples	5



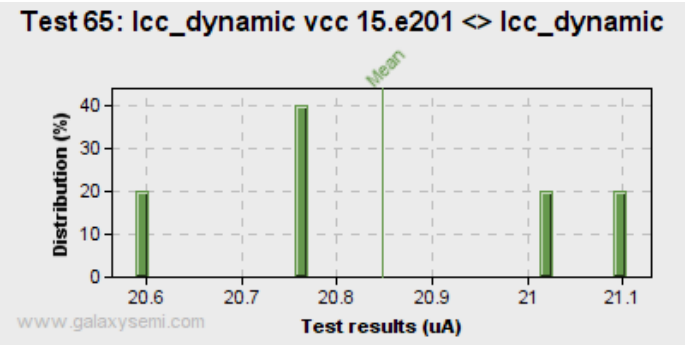
Test	62
Name	OutputZ_leak_vbt1 p73 19.e108
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	5 / 0 (0.00%)
Mean	0.00144829 uA
Sigma	0.00513039 uA
Range	0.0129584 uA
Cp / Cpk	974.6 / 649.8
Samples	5



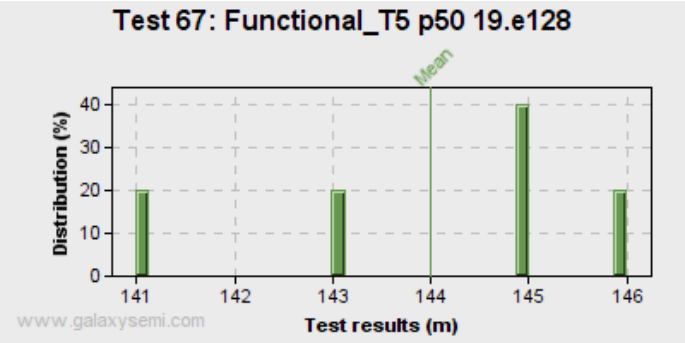
Test	64
Name	icc_static_vbt11 vcc 15.e201 <> Icc_static
Test type	Parametric
Low limit	10 uA
High limit	500 uA
Exec / Fails	5 / 0 (0.00%)
Mean	21.2076 uA
Sigma	0.186076 uA
Range	0.514983 uA
Cp / Cpk	438.9 / 20.08
Samples	5



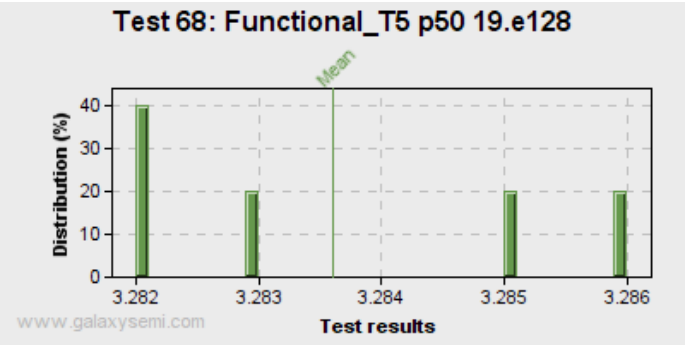
Test	65
Name	Icc_dynamic vcc 15.e201 <> Icc_dynamic
Test type	Parametric
Low limit	10 uA
High limit	500 uA
Exec / Fails	5 / 0 (0.00%)
Mean	20.8471 uA
Sigma	0.210242 uA
Range	0.514985 uA
Cp / Cpk	388.4 / 17.20
Samples	5



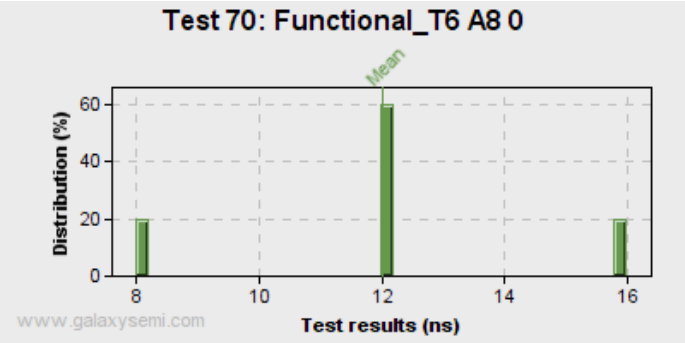
Test	67
Name	Functional_T5 p50 19.e128
Test type	Parametric
Low limit	0 m
High limit	500 m
Exec / Fails	5 / 0 (0.00%)
Mean	144 m
Sigma	2 m
Range	5 m
Cp / Cpk	41.67 / 24.00
Samples	5



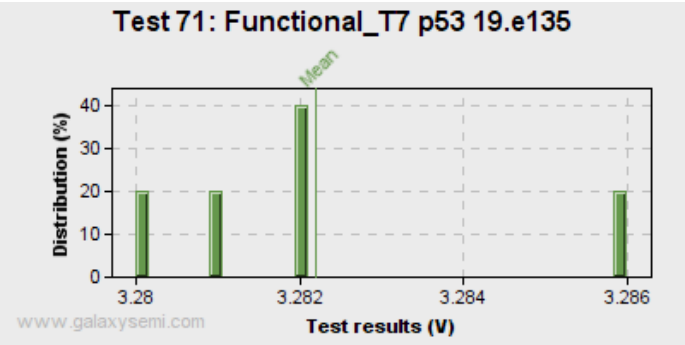
Test	68
Name	Functional_T5 p50 19.e128
Test type	Parametric
Low limit	2.8
High limit	3.4
Exec / Fails	5 / 0 (0.00%)
Mean	3.2836
Sigma	0.00181658
Range	0.00399995
Cp / Cpk	55.05 / 21.36
Samples	5



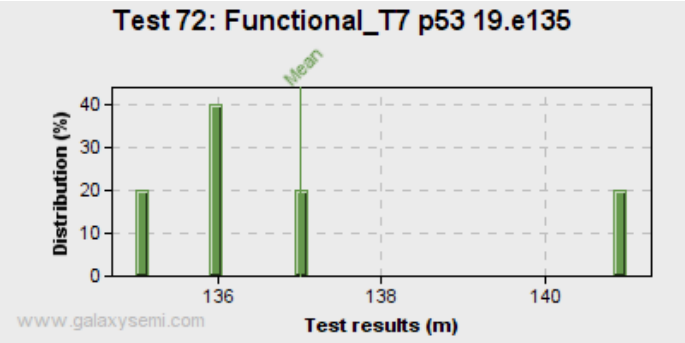
Test	70
Name	Functional_T6 A8 0
Test type	Parametric
Low limit	1 ns
High limit	100 ns
Exec / Fails	5 / 0 (0.00%)
Mean	12 ns
Sigma	2.82843 ns
Range	8 ns
Cp / Cpk	5.83 / 1.30
Samples	5



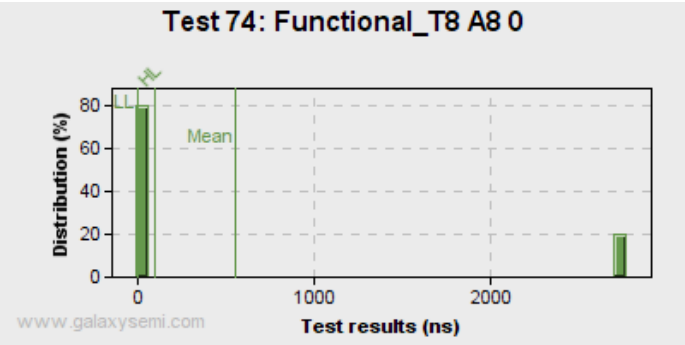
Test	71
Name	Functional_T7 p53 19.e135
Test type	Parametric
Low limit	2.5 V
High limit	3.5 V
Exec / Fails	5 / 0 (0.00%)
Mean	3.2822 V
Sigma	0.00228037 V
Range	0.00600004 V
Cp / Cpk	73.09 / 31.84
Samples	5



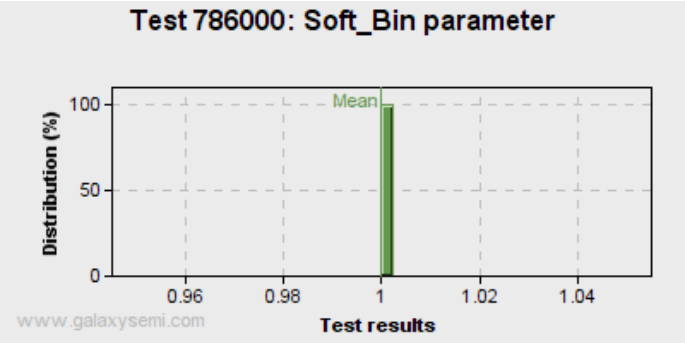
Test	72
Name	Functional_T7 p53 19.e135
Test type	Parametric
Low limit	0 m
High limit	500 m
Exec / Fails	5 / 0 (0.00%)
Mean	137 m
Sigma	2.34521 m
Range	6 m
Cp / Cpk	35.53 / 19.47
Samples	5



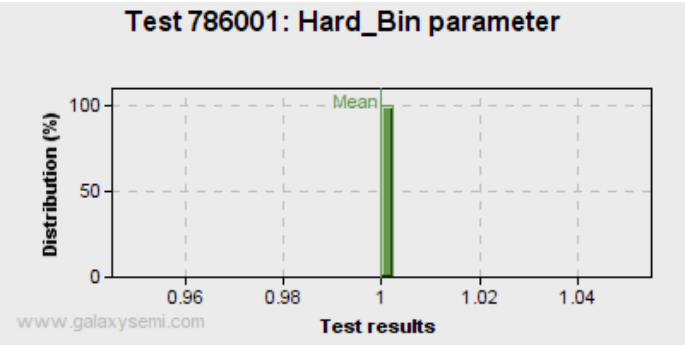
Test	74
Name	Functional_T8 A8 0
Test type	Parametric
Low limit	1 ns
High limit	100 ns
Exec / Fails	5 / 3 (60.00%)
Mean	**556 ns**
Sigma	1236.55 ns
Range	2770 ns
Cp / Cpk	0.0133 / −0.1229 ....=&gt Warning: Process is over the high limit
Samples	5



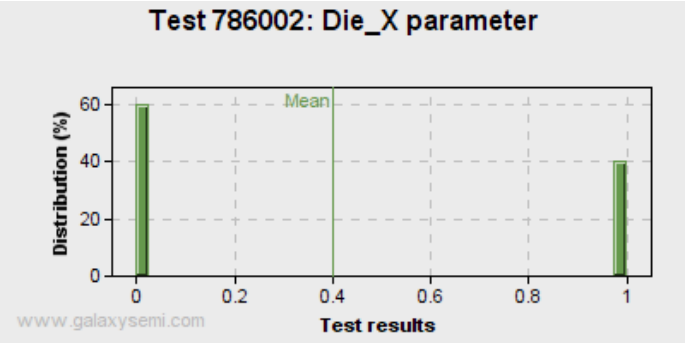
Test	786000
Name	Soft_Bin parameter
Test type	–
Low limit	n/a .
High limit	n/a .
Exec / Fails	5 / 0 (0.00%)
Mean	1
Sigma	0
Range	0
Cp / Cpk	n/a . / n/a .
Samples	5



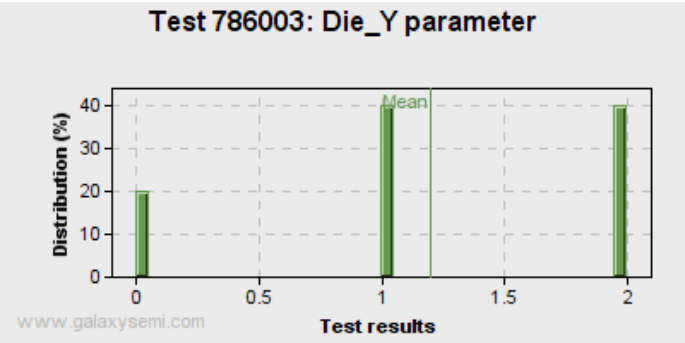
Test	786001
Name	Hard_Bin parameter
Test type	–
Low limit	n/a .
High limit	n/a .
Exec / Fails	5 / 0 (0.00%)
Mean	1
Sigma	0
Range	0
Cp / Cpk	n/a . / n/a .
Samples	5



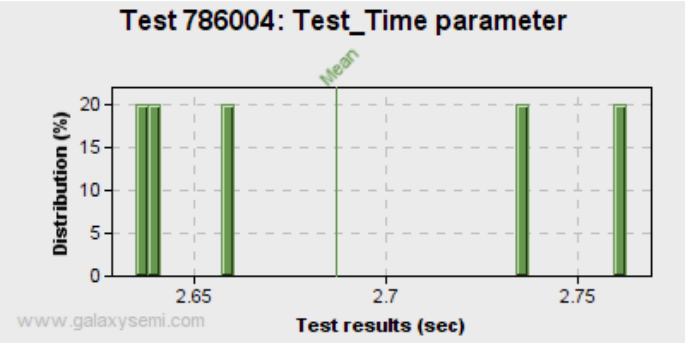
Test	786002
Name	Die_X parameter
Test type	–
Low limit	n/a .
High limit	n/a .
Exec / Fails	5 / 0 (0.00%)
Mean	0.4
Sigma	0.547723
Range	1
Cp / Cpk	n/a . / n/a .
Samples	5



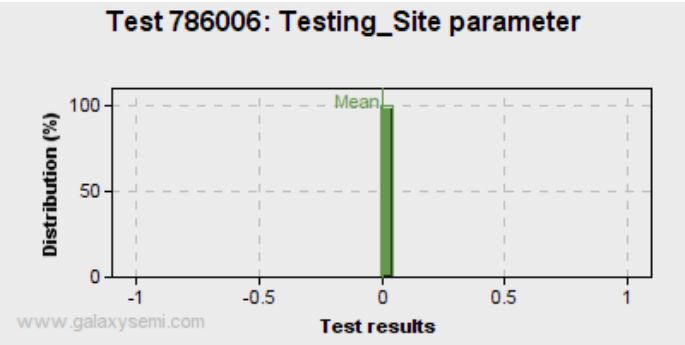
Test	786003
Name	Die_Y parameter
Test type	–
Low limit	n/a .
High limit	n/a .
Exec / Fails	5 / 0 (0.00%)
Mean	1.2
Sigma	0.83666
Range	2
Cp / Cpk	n/a . / n/a .
Samples	5



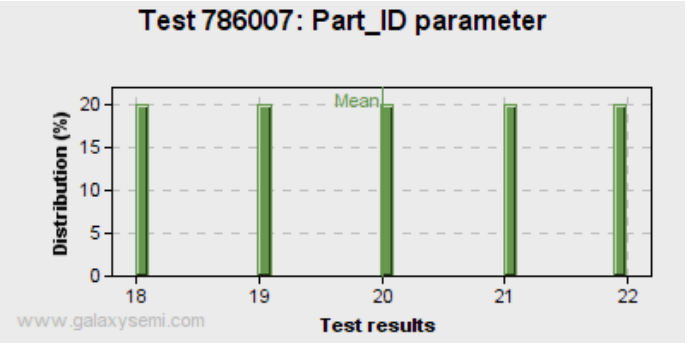
Test	786004
Name	Test_Time parameter
Test type	–
Low limit	0.0 sec
High limit	n/a .
Exec / Fails	5 / 0 (0.00%)
Mean	2.687 sec
Sigma	0.0589067 sec
Range	0.128 sec
Cp / Cpk	n/a . / 15.20
Samples	5



Test	786006
Name	Testing_Site parameter
Test type	–
Low limit	n/a .
High limit	n/a .
Exec / Fails	5 / 0 (0.00%)
Mean	0
Sigma	0
Range	0
Cp / Cpk	n/a . / n/a .
Samples	5



Test	786007
Name	Part_ID parameter
Test type	–
Low limit	n/a .
High limit	n/a .
Exec / Fails	5 / 0 (0.00%)
Mean	20
Sigma	1.58114
Range	4
Cp / Cpk	n/a . / n/a .
Samples	5



Pareto of Tests Cp

Test	Name	Cp	Test Cp Chart
74	Functional_T8 A8 0	0.0133	

Shows all Cp <= 1.7 (Defined in Options , section 'Pareto/Define Cp cut−off limit')

Pareto of Tests Cpk

Test	Name	Cpk	Test Cpk Chart
74	Functional_T8 A8 0	−0.1229	
70	Functional_T6 A8 0	1.30	

Shows all Cpk <= 1.3 (Defined in Options , section 'Pareto/Define Cp cut−off limit')

Pareto of Tests failures

Test	Name	Failing Bin	Failures count	Yield Loss	Fail contribution	Test Fail rate	Failures Chart
74	Functional_T8 A8 0	–	3	13.6 %	n/a	60.0 %	
80	Functional_T7	–	2	9.1 %	n/a	n/a	
75	Functional_T7	–	1	4.5 %	n/a	n/a	
79	Functional_T8	–	1	4.5 %	n/a	n/a	
81	Functional_T7	–	1	4.5 %	n/a	n/a	
82	Functional_T8	–	1	4.5 %	n/a	n/a	
83	Functional_T7	–	1	4.5 %	n/a	n/a	
85	Functional_T8	–	1	4.5 %	n/a	n/a	
87	Functional_T8	–	1	4.5 %	n/a	n/a	
89	Functional_T8	–	1	4.5 %	n/a	n/a	
92	Functional_T8	–	1	4.5 %	n/a	n/a	
93	Functional_T8	–	1	4.5 %	n/a	n/a	
–	**Cumul. of failures**	–	**15**	**68.2 %**	**0.0 %**	**60.0 %**	

–– Yield loss: number of failed test executions / number of parts
–– Fail contribution: number of failed test executions / number of parts failed
–– Test Fail rate: number of failed test executions / number of test executions

Pareto of Functional Failure Signatures (pins tested in parallel)

Total devices tested: **22**
Total patterns detected: **1**

Fail count	% of failures	% of tested	Functional Failure signatures (tested pins failing together)
3	100.00 %	13.64 %	Functional_T8 A8 0 (Test 74)
3	**100 %**	**–**	**Total failures detected**

Shows first 25 % of the failure signatures (Defined in Options, section 'Pareto/Define Failure Signatures cut−off limit')

Pareto of Parametric Failure Signatures (tests failing concurrently)

No Parametric failure signature detected

Pareto of Software Bins

Software Binning	Bin Name	Count	Percentage	Software Binning Chart
1	–	22	100.0 %	
Cumul.	Cumul.	22	100.0%	

Pareto of Hardware Bins

Hardware Binning	Bin Name	Count	Percentage	Hardware Binning Chart
1	–	22	100.0 %	
Cumul.	Cumul.	22	100.0%	

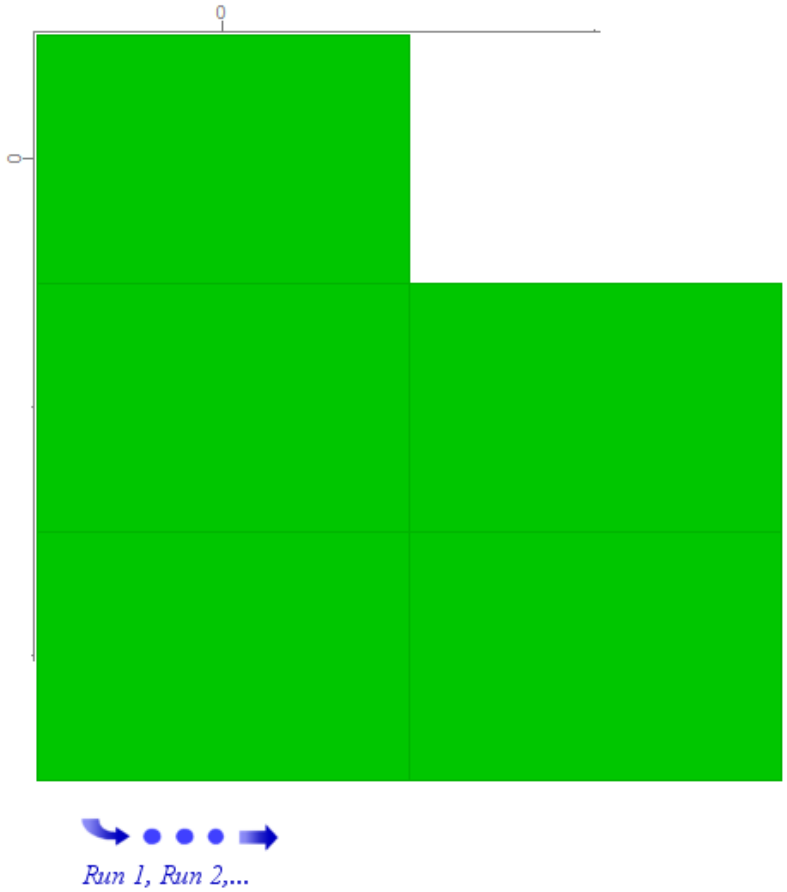
Wafermaps & Strip Maps

Map type	Show Software bins
Devices tested (with retests)	22
Total physical parts tested	5 (only applies to Wafermaps)

List of Individual Maps

Top 10 Software Binning	1
Color	
Pass/Fail	P
Percentage	100.0%
Total count	22

Map style	STRIP map (parts tested are PACKAGED DEVICES!)
Total physical parts tested	5
Parts processed	All Data / parts (any Bin)
Data from Sites	All sites
Strip started	Tue Sep 03 12:19:53 2024
Strip ended	Tue Sep 03 12:20:42 2024
Wafer tested in	49 seconds
Average device test time	2.227 sec.
Map dimensions	LowX=0, LowY=0, HighX=1, HighY=2



Software Binning Summary

Software Binning	Bin Name	Pass/ Fail	Total count	Percentage	Software Binning Chart
1	–	P	22	100.0 %	
All PASS Bins	**All PASS Bins**	P	**22**	**100.0 %**	
ALL Bins	**ALL Bins**	–	**22**	**100.0 %**	

Hint: From the 'Options' tab in the 'Binning' section, you can configure how to compute the binning (from summary or samples)

Hardware Binning Summary

Hardware Binning	Bin Name	Pass/ Fail	Total count	Percentage	Hardware Binning Chart
1	–	P	22	100.0 %	
All PASS Bins	All PASS Bins	P	22	100.0 %	
ALL Bins	ALL Bins	–	22	100.0 %	

Hint: From the 'Options' tab in the 'Binning' section, you can configure how to compute the binning (from summary or samples)

Message Log

No log message to report

Global Information

Report from	Teradyne–Examinator–Pro+ – V8.1.5 – www.galaxysemi.com
Report created	Tue Sep 03 00:21:21 2024
Data processed	35.1 KB (35940 bytes)
Processing time	1.31 second
Processing speed	27.2 KB/sec
Examinator expires	Sat Sep 2 2034
(null)	–
File name	C:/Users/rahmana/OneDrive – Teradyne/Desktop/New Hire/New Hire Tech/UFP New Hire Train/Project 1/i8243/results_v4_5loop_1.std
Tests mapping file	n/a

Setup time	Tue Sep 03 12:19:53 2024
Start time	Tue Sep 03 12:19:53 2024
End time	Tue Sep 03 12:20:42 2024
Test duration	49 seconds
Product	n/a
Program	rahmana_i8243_p1.igxl
Revision	n/a
Lot	n/a
Sub−Lot	n/a
WaferID	n/a
Parts processed	All Data / parts (any Bin)
Data from Sites	All sites
Test time (GOOD parts)	2.687 sec. (excludes tester idle time)
Test time (ALL parts)	2.687 sec. (excludes tester idle time)
Average test time	2.227 sec. / device (includes tester idle time between parts)
Total parts tested	22 − Includes parts retested (if any)
Good parts (Yield)	22 (100.00%) − Includes parts retested (if any)
Bad parts (Yield loss)	0 (0.00%) − Includes parts retested (if any)
Parts retested	n/a .
Parts aborted	0 (0.00%)
(null)	−
STDF Version	4.0
Tester name	SNG−UFP−789
Tester type	UltraFLEXplus
Station	1
Part type	n/a
Operator	rahmana
Exec_type	IG−XL
Exec_version	10.30.10_uflx (P1.11)
TestCode	n/a
Test Temperature	n/a
User Text	n/a
Aux_file	n/a
Package type	n/a
Per_freq	n/a
Spec_name	n/a
Spec_version	n/a
Family ID	n/a

Date code	n/a
Design Rev	n/a
Facility ID	n/a
Floor ID	n/a
Proc ID	n/a
Flow ID	n/a
Setup ID	n/a
Eng ID	n/a
ROM code	n/a
Serial #	n/a
Super user name	n/a
Handler/Prober	n/a
(null)	–
Site details	Site# 0

Global Options

Test# policy	Never merge tests with identical test number if test name not matching
Data Cleaning	None (keep all data)
Statistics computation	From samples data (if any), otherwise from summary
Binning computation	From summary data (if any), otherwise from samples
Cp,Cpk computation	Use standard Sigma formula
Mean drift formula	Percentage of value drift